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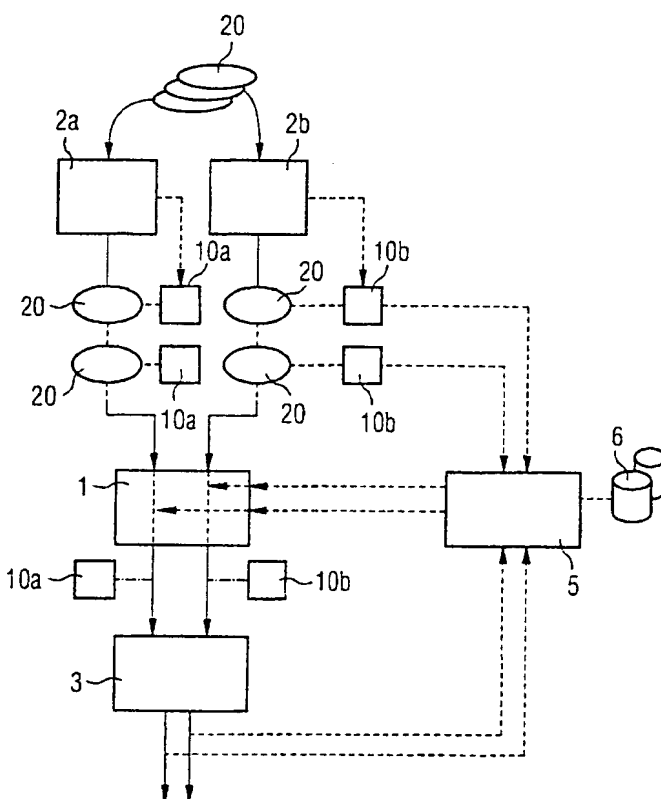
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(54) Title: METHOD FOR ADJUSTING PROCESSING PARAMETERS OF AT LEAST ONE PLATE-LIKE OBJECT IN A PROCESSING TOOL



(57) Abstract: Processing parameters of at least one plate-like object (20), e.g. a semiconductor device or wafer, or a flat panel display, in a processing tool (1) are adjusted depending on which processing device (2a) out of at least one set of processing devices (2a, 2b) has been used for the semiconductor device (20) in a preceding step. This is provided by generating a virtual or physical token (10a), which connects the semiconductor device (20) identification with the processing device (2a, 2b) identification. This enables a compensation of tool-dependent effects in previous processing of a single device. An example is chemical mechanical polishing prior to lithography, where alignment marks can be deteriorated differently between CMP-apparatus. The amount of compensation is detected and evaluated by means of metrology tools, which - depending on the sequence of the metrology step relative to the processing step to be adjusted - either feed-forward or feed-backward their results to the processing tool (1). The yield of semiconductor device production is advantageously increased.

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